

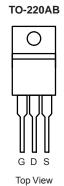
## BUK555-50B-VB Datasheet N-Channel 60 V (D-S) MOSFET

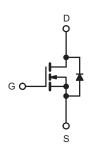
PRODUCT SUMMARY					
V <sub>DS</sub> (V)	$R_{DS(on)}(\Omega)$	I <sub>D</sub> (A) <sup>a</sup>			
60	0.024 at V <sub>GS</sub> = 10 V	50			
	0.028 at V <sub>GS</sub> = 4.5 V	40			

#### **FEATURES**

- Halogen-free According to IEC 61249-2-21 **Definition**
- Surface Mount
- Available in Tape and Reel
- Dynamic dV/dt Rating
- Logic-Level Gate Drive
- Fast Switching
- Compliant to RoHS Directive 2002/95/EC







N-Channel MOSFET

<b>ABSOLUTE MAXIMUM RATINGS</b> (T <sub>C</sub> = 25 °C, unless otherwise noted)						
PARAMETER			SYMBOL	LIMIT	UNIT	
Drain-Source Voltage			$V_{DS}$	60	V	
Gate-Source Voltage			$V_{GS}$	± 20	V	
Continuous Drain Current <sup>f</sup>	V <sub>GS</sub> at 10 V	$T_{\rm C} = 25  ^{\circ}{\rm C}$ $T_{\rm C} = 100  ^{\circ}{\rm C}$	L	50		
Continuous Drain Current	V <sub>GS</sub> at 10 V	T <sub>C</sub> = 100 °C	I <sub>D</sub>	36	Α	
Pulsed Drain Current <sup>a</sup>			I <sub>DM</sub>	200		
Linear Derating Factor				1.0	W/°C	
Linear Derating Factor (PCB Mount)e				0.025	VV/ C	
Single Pulse Avalanche Energy <sup>b</sup>			E <sub>AS</sub>	400	mJ	
Maximum Power Dissipation	T <sub>C</sub> = 25 °C		0	150	W	
Maximum Power Dissipation (PCB Mount)e	T <sub>A</sub> = 25 °C		$P_{D}$	3.7		
Peak Diode Recovery dV/dtc	dV/dt	4.5	V/ns			
Operating Junction and Storage Temperature Range			T <sub>J</sub> , T <sub>stg</sub>	- 55 to + 175	°C	
Soldering Recommendations (Peak Temperature) <sup>d</sup> for 10 s				300 <sup>d</sup>	<u> </u>	

- a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11). b.  $V_{DD} = 25$  V, starting  $T_J = 25$  °C, L = 179  $\mu$ H,  $R_g = 25$   $\Omega$ ,  $I_{AS} = 51$  A (see fig. 12). c.  $I_{SD} \le 51$  A,  $I_{AS} = 51$

- d. 1.6 mm from case.
- e. When mounted on 1" square PCB (FR-4 or G-10 material).
- f. Current limited by the package, (die current = 51 A).



THERMAL RESISTANCE RATINGS						
PARAMETER	SYMBOL	TYP.	MAX.	UNIT		
Maximum Junction-to-Ambient	R <sub>thJA</sub>	-	62			
Maximum Junction-to-Ambient (PCB Mount) <sup>a</sup>	R <sub>thJA</sub>	-	40	°C/W		
Maximum Junction-to-Case (Drain)	R <sub>thJC</sub>	-	1.0			

Note
a. When mounted on 1" square PCB (FR-4 or G-10 material).

SPECIFICATIONS (T <sub>J</sub> = 25 °C, t		-		1		I	ı	
PARAMETER	SYMBOL	TEST CONDITIONS		MIN.	TYP.	MAX.	UNIT	
Static								
Drain-Source Breakdown Voltage	$V_{DS}$	$V_{GS}$	= 0, I <sub>D</sub> = 250 μA	60	-	-	V	
V <sub>DS</sub> Temperature Coefficient	$\Delta V_{DS}/T_{J}$	Reference to 25 °C, I <sub>D</sub> = 1 mA		-	0.070	-	V/°C	
Gate-Source Threshold Voltage	V <sub>GS(th)</sub>	V <sub>DS</sub> =	$V_{GS}$ , $I_D = 250 \mu A$	1.0	-	2.5		
Gate-Source Leakage	I <sub>GSS</sub>	V <sub>GS</sub> = ± 10 V		-	-	± 100	nA	
Zana Oata Valta na Busin Ouwant	I <sub>DSS</sub>	$V_{DS} = 60 \text{ V}, V_{GS} = 0 \text{ V}$		-	-	25	μА	
Zero Gate Voltage Drain Current		$V_{DS} = 48 V_{s}$	V <sub>DS</sub> = 48 V, V <sub>GS</sub> = 0 V, T <sub>J</sub> = 150 °C		-	250		
Drain Source On State Besistance	В	V <sub>GS</sub> = 10 V	I <sub>D</sub> = 21 A <sup>b</sup>	-	0.024	-		
Drain-Source On-State Resistance	R <sub>DS(on)</sub>	V <sub>GS</sub> = 4.5 V	I <sub>D</sub> = 15 A <sup>b</sup>	-	0.028	-	Ω	
Forward Transconductance	9 <sub>fs</sub>	V <sub>DS</sub> :	= 25 V, I <sub>D</sub> = 21A <sup>b</sup>	23	-	-	S	
Dynamic								
Input Capacitance	C <sub>iss</sub>		V <sub>GS</sub> = 0 V,	-	190			
Output Capacitance	C <sub>oss</sub>	$V_{DS} = 25 \text{ V},$ $V_{DS} = 25 \text{ V},$ $f = 1.0 \text{ MHz}, \text{ see fig. 5}$		-	920	-	pF	
Reverse Transfer Capacitance	C <sub>rss</sub>			-	170	-		
Total Gate Charge	Qg			-	-	66	nC	
Gate-Source Charge	$Q_{gs}$	$V_{GS} = 5.0 \text{ V}$	$V_{GS} = 5.0 \text{ V}$ $I_D = 51 \text{ A}, V_{DS} = 48 \text{ V},$ see fig. 6 and 13 <sup>b</sup>		-	12		
Gate-Drain Charge	$Q_{gd}$		goo ngi o ana io	-	-	43		
Turn-On Delay Time	t <sub>d(on)</sub>			-	17	-		
Rise Time	t <sub>r</sub>	V <sub>DD</sub> :	= 30 V, I <sub>D</sub> = 51 A,	-	230	-	]	
Turn-Off Delay Time	t <sub>d(off)</sub>	$R_g$ = 4.6 $Ω$ , $R_D$ = 0.56 $Ω$ , see fig. 10 <sup>b</sup>		-	2	-	- ns	
Fall Time	t <sub>f</sub>			-	110	-		
Internal Drain Inductance	L <sub>D</sub>	Between lead, 6 mm (0.25") from package and center of die contact		-	4.5	-	nU.	
Internal Source Inductance	L <sub>S</sub>			-	7.5	1	nH	
<b>Drain-Source Body Diode Characteristic</b>	cs							
Continuous Source-Drain Diode Current	I <sub>S</sub>	MOSFET symbol showing the integral reverse p - n junction diode		-	-	50 <sup>c</sup>	A	
Pulsed Diode Forward Current <sup>a</sup>	I <sub>SM</sub>			-	-	200		
Body Diode Voltage	V <sub>SD</sub>	T <sub>J</sub> = 25 °C, I <sub>S</sub> = 51 A, V <sub>GS</sub> = 0 V <sup>b</sup>		-	-	2.5	V	
Body Diode Reverse Recovery Time	t <sub>rr</sub>	T <sub>J</sub> = 25 °C, I <sub>F</sub> = 51 A, dl/dt = 100 A/μs <sup>b</sup>		-	130	180	ns	
Body Diode Reverse Recovery Charge	Q <sub>rr</sub>			-	0.84	1.3	μC	
Forward Turn-On Time	t <sub>on</sub>	Intrinsic turn-on time is negligible (turn-on is dominated by L <sub>S</sub> and L <sub>D</sub> )					1 _ \	

### Notes

- a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11).
  b. Pulse width ≤ 300 μs; duty cycle ≤ 2 %.
  c. Current limited by the package, (Die Current = 51 A).



### TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)



Fig. 1 - Typical Output Characteristics,  $T_C = 25$  °C

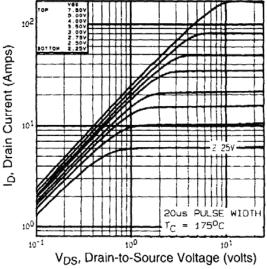


Fig. 2 - Typical Output Characteristics,  $T_C = 150 \, ^{\circ}C$ 

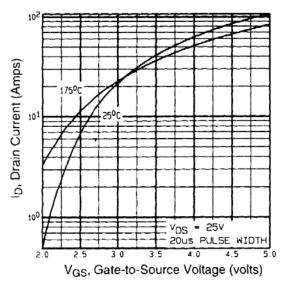


Fig. 3 - Typical Transfer Characteristics

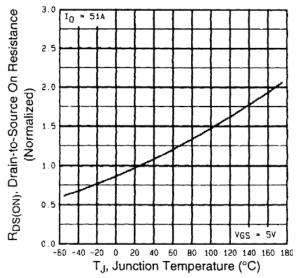


Fig. 4 - Normalized On-Resistance vs. Temperature



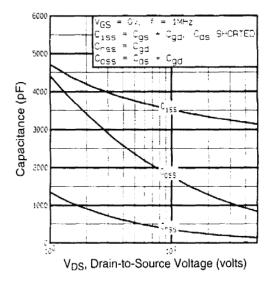


Fig. 5 - Typical Capacitance vs. Drain-to-Source Voltage

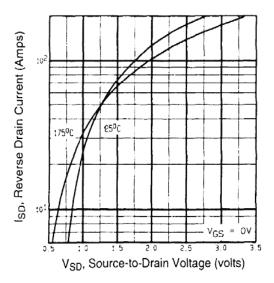


Fig. 7 - Typical Source-Drain Diode Forward Voltage

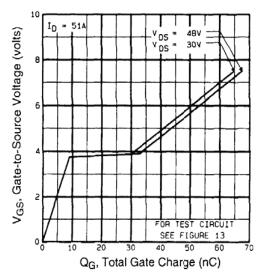


Fig. 6 - Typical Gate Charge vs. Gate-to-Source Voltage

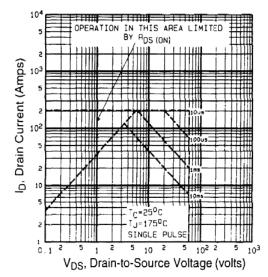


Fig. 8 - Maximum Safe Operating Area



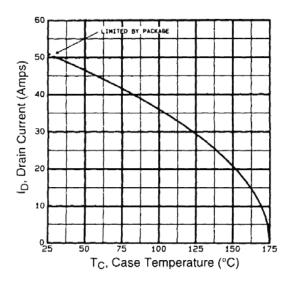


Fig. 9 - Maximum Drain Current vs. Case Temperature

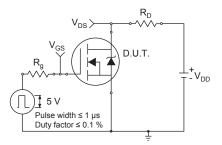


Fig. 10a - Switching Time Test Circuit

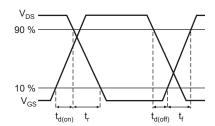


Fig. 10b - Switching Time Waveforms

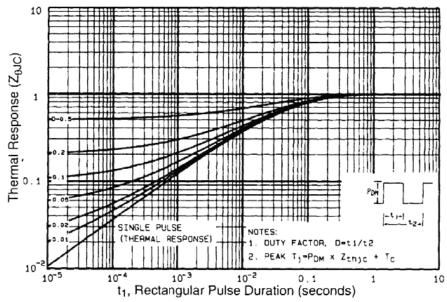
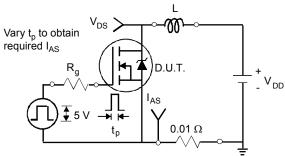
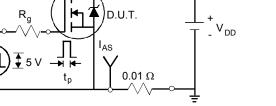


Fig. 11 - Maximum Effective Transient Thermal Impedance, Junction-to-Case







 $V_{DS}$  $V_{\text{DD}}$ 

Fig. 12a - Unclamped Inductive Test Circuit

Fig. 12b - Unclamped Inductive Waveforms

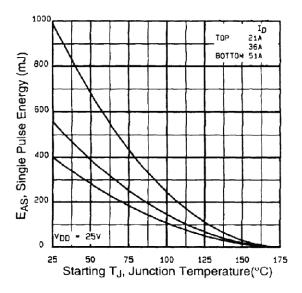


Fig. 12c - Maximum Avalanche Energy vs. Drain Current

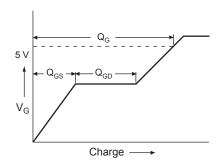


Fig. 13a - Basic Gate Charge Waveform

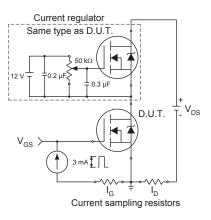
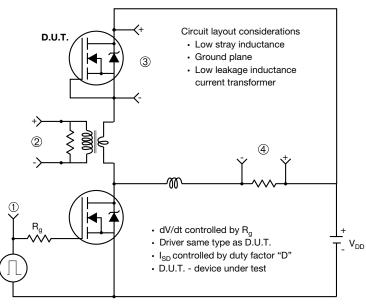


Fig. 13b - Gate Charge Test Circuit



#### Peak Diode Recovery dV/dt Test Circuit



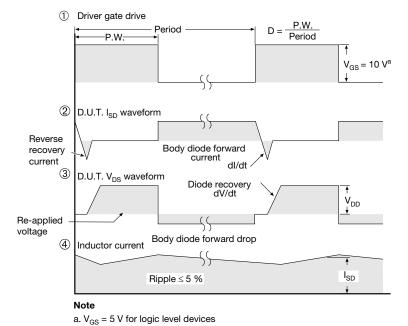
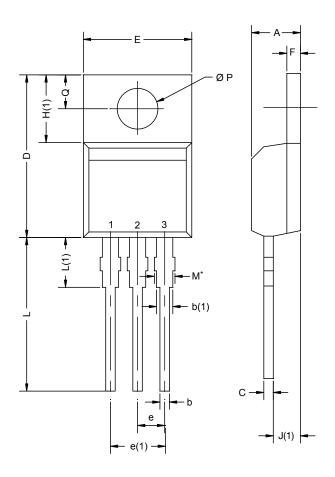


Fig. 14 - For N-Channel



### **TO-220AB**



	MILLIN	IETERS	INC	HES		
DIM.	MIN.	MAX.	MIN.	MAX.		
Α	4.25	4.65	0.167	0.183		
b	0.69	1.01	0.027	0.040		
b(1)	1.20	1.73	0.047	0.068		
С	0.36	0.61	0.014	0.024		
D	14.85	15.49	0.585	0.610		
Е	10.04	10.51	0.395	0.414		
е	2.41	2.67	0.095	0.105		
e(1)	4.88	5.28	0.192	0.208		
F	1.14	1.40	0.045	0.055		
H(1)	6.09	6.48	0.240	0.255		
J(1)	2.41	2.92	0.095	0.115		
L	13.35	14.02	0.526	0.552		
L(1)	3.32	3.82	0.131	0.150		
ØР	3.54	3.94	0.139	0.155		
Q	2.60	3.00	0.102	0.118		
ECN: X12-0208-Rev. N, 08-Oct-12						

ECN: X12-0208-Rev. N, 08-Oct-12 DWG: 5471

## Notes

# $^{\star}$ M = 1.32 mm to 1.62 mm (dimension including protrusion) Heatsink hole for HVM



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